

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination GIST ET AL.	
		Examiner Luke Osborne	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,933,356 A	08-1999	Rostoker et al.	703/15
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nourani, Mehrdad et al, "Built-In Self-Test for Signal Integrity" ACM June 18, 2001 pages 792-797
	V	"Inside differential signals" by Cadence, 2001, retrieved from www.winnet.com.cn/Cadence/High_Speed_Design/Inside_Differential_Signals.pdf on 7/10/05 4 pages
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.